## Notice of References Cited Application/Control No. 10/840,092 Examiner Van T. Trieu Applicant(s)/Patent Under Reexamination HANSON ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,148,803	12-2006	Bandy et al.	340/539.16
*	В	US-7,136,832	11-2006	Li et al.	705/34
*	С	US-7,129,837	10-2006	Shannon et al.	340/539.13
*	D	US-7,057,512	06-2006	Stilp, Louis A.	340/572.1
*	Е	US-6,965,816	11-2005	Walker, Richard C.	701/16
*	F	US-6,954,148	10-2005	Pulkkinen et al.	340/572.1
*	G	US-6,591,084	07-2003	Chuprun et al.	455/3.05
*	Н	US-6,566,997	05-2003	Bradin, John P.	340/10.2
	1	US-			
	٦	US-			
	К	US-			
	L	US-			
	М	US-			<u> </u>

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	s					
	Τ					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.